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Nederlandse norm

# NEN-ISO 20720

(en)

Microbeam analysis - Methods of specimen preparation for analysis of general powders using WDS and EDS (ISO 20720:2018, IDT)

ICS 71.040.99  
november 2018

Als Nederlandse norm is aanvaard:

- ISO 20720:2018, IDT

Normcommissie 342202 'Begeleiding ISO/TC202'



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**Microbeam analysis — Methods of  
specimen preparation for analysis of  
general powders using WDS and EDS**

*Analyse par microfaisceaux — Méthodes de préparation des  
échantillons pour l'analyse des particules*



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# Contents

	Page
Foreword.....	iv
Introduction.....	v
<b>1 Scope</b> .....	<b>1</b>
<b>2 Normative references</b> .....	<b>1</b>
<b>3 Terms and definitions</b> .....	<b>1</b>
<b>4 Abbreviated terms</b> .....	<b>1</b>
<b>5 Analytical purposes and methods of specimen preparation for particle analysis<sup>[1]</sup></b> .....	<b>1</b>
5.1 Methods of specimen preparation for particle analysis.....	1
5.2 Description of preparation methods.....	2
5.2.1 Analysis of whole particles or surface of particles.....	2
5.2.2 Analysis of cross-section of particles.....	4
5.3 Choosing preparation methods.....	5
<b>6 Electric conductivity processing</b> .....	<b>6</b>
<b>Annex A (informative) Examples of X-ray strength dependency on tablet-forming pressure</b> .....	<b>7</b>
<b>Annex B (informative) Example of X-ray strength dependency on tablet-forming particle size</b> .....	<b>8</b>
<b>Bibliography</b> .....	<b>9</b>

## Foreword

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This document was prepared by Technical Committee ISO/TC 202, *Microbeam analysis*.

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